Electronic Supplementary Material (ESI) for New Journal of Chemistry.

Supporting Information

Networked Mixed Metal Oxide (V^{+4} and Ti^{+4}) Nanostructures as Potential Material for Trimethylamine Detection

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S1: XPS magnified survey spectra

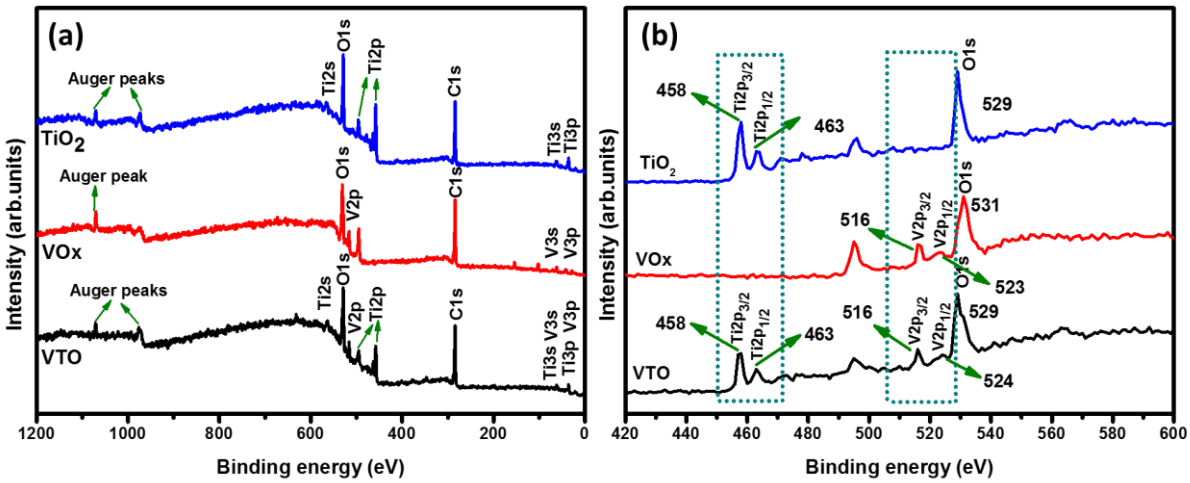

Fig:1 XPS (a) surface survey scan spectra and its (b) magnified spectra, corresponding to TiO_2, VO_2 and VTO thin films

S2: XPS Depth Profile studies of TiO_2 and VO_2

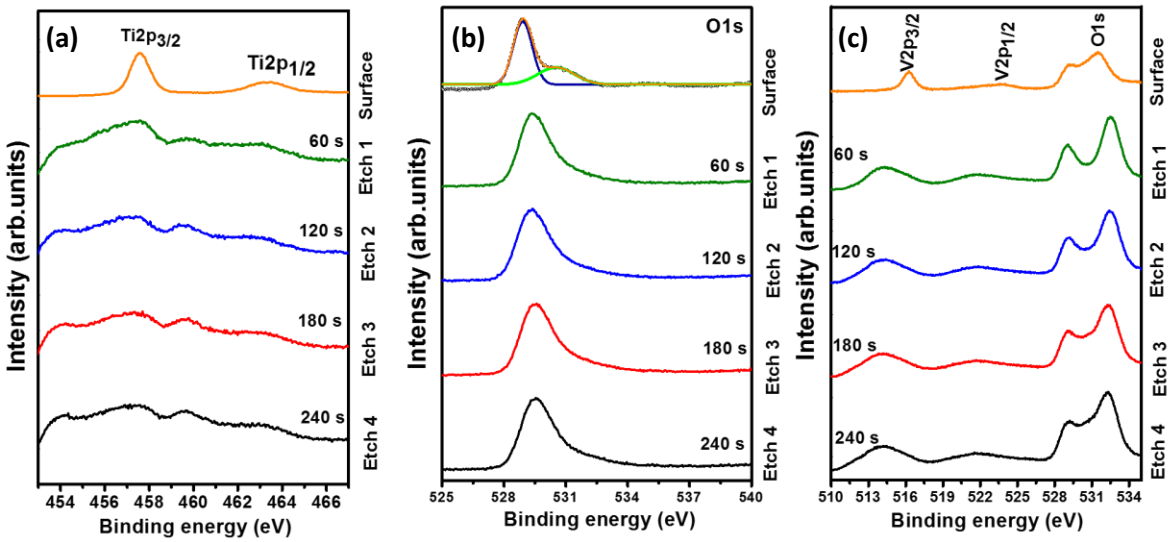

Fig: 2 XPS depth profiling plot - narrow scan spectra corresponding to (a) Ti2p & (b) O1s of TiO_2 and (c) V2p & O1s of VO_2 thin films

S3: EDS Mapping

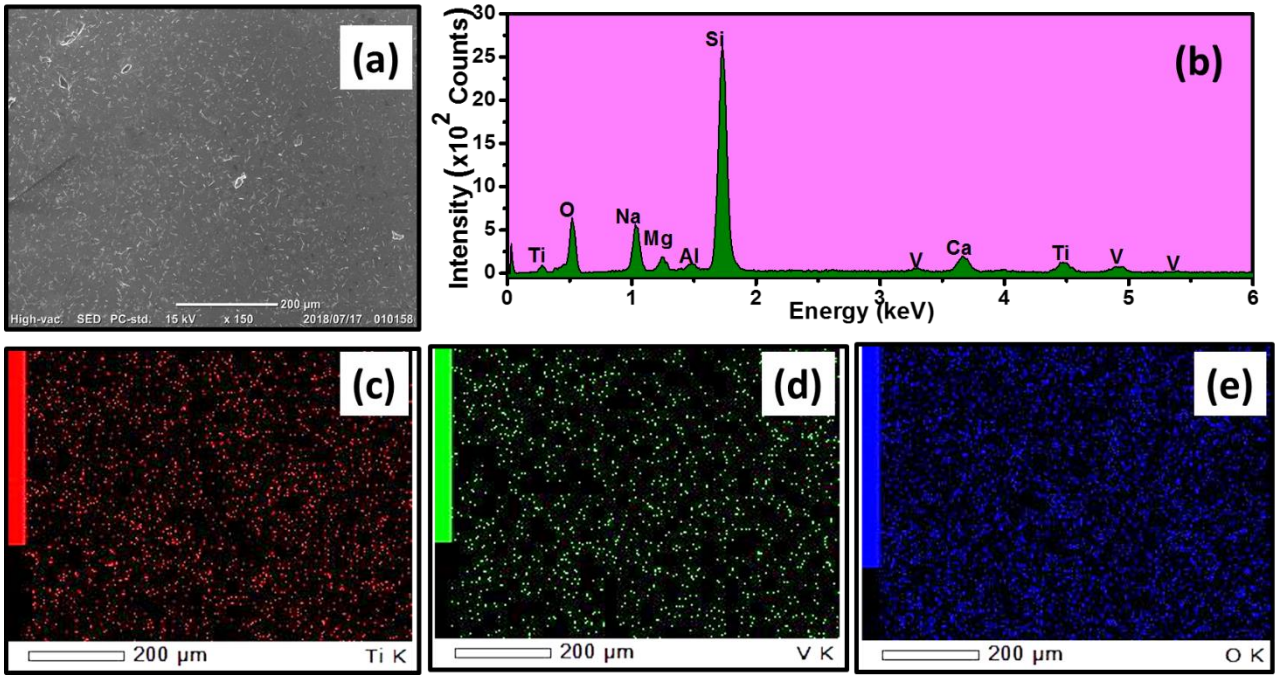

Fig. 3 (a) SEM micrograph (b) EDS spectra, mappings of (c) Ti (d) V and (e) O, of VTO thin film